# MOSFET – Power, Single, N-Channel 40 V, 2.8 m $\Omega$ , 110 A

### **Features**

- Small Footprint (5x6 mm) for Compact Design
- Low R<sub>DS(on)</sub> to Minimize Conduction Losses
- Low Q<sub>G</sub> and Capacitance to Minimize Driver Losses
- LFPAK Package, Industry Standard
- These Devices are Pb-Free and are RoHS Compliant

# **MAXIMUM RATINGS** (T<sub>J</sub> = 25°C unless otherwise noted)

Parameter			Symbol	Value	Unit
Drain-to-Source Voltage			$V_{DSS}$	40	٧
Gate-to-Source Voltage	Э		$V_{GS}$	±20	V
Continuous Drain		T <sub>C</sub> = 25°C	I <sub>D</sub>	110	Α
Current R <sub>θJC</sub> (Notes 1, 3)	Steady	T <sub>C</sub> = 100°C		81	
Power Dissipation	State	T <sub>C</sub> = 25°C	P <sub>D</sub>	68	W
R <sub>θJC</sub> (Note 1)		T <sub>C</sub> = 100°C		34	
Continuous Drain		T <sub>A</sub> = 25°C	I <sub>D</sub>	27	Α
Current R <sub>0JA</sub> (Notes 1, 2, 3)	Steady	T <sub>A</sub> = 100°C		19	
Power Dissipation	State	T <sub>A</sub> = 25°C	$P_{D}$	3.7	W
R <sub>θJA</sub> (Notes 1, 2)		T <sub>A</sub> = 100°C		1.6	
Pulsed Drain Current	$T_A = 25^{\circ}C, t_p = 10 \mu s$		I <sub>DM</sub>	740	Α
Operating Junction and Storage Temperature Range			T <sub>J</sub> , T <sub>stg</sub>	-55 to + 175	°C
Source Current (Body Diode)			I <sub>S</sub>	76	Α
Single Pulse Drain-to-Source Avalanche Energy (I <sub>L(pk)</sub> = 7 A)			E <sub>AS</sub>	215	mJ
Lead Temperature for Soldering Purposes (1/8" from case for 10 s)		TL	260	°C	

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

# THERMAL RESISTANCE MAXIMUM RATINGS

Parameter	Symbol	Value	Unit
Junction-to-Case - Steady State	$R_{\theta JC}$	2.2	°C/W
Junction-to-Ambient - Steady State (Note 2)	$R_{\theta JA}$	39	

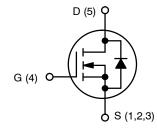
- The entire application environment impacts the thermal resistance values shown, they are not constants and are only valid for the particular conditions noted.
- 2. Surface-mounted on FR4 board using a 650 mm<sup>2</sup>, 2 oz. Cu pad.
- Maximum current for pulses as long as 1 second is higher but is dependent on pulse duration and duty cycle.



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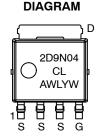
V <sub>(BR)DSS</sub>	R <sub>DS(ON)</sub> MAX	I <sub>D</sub> MAX	
40 V	2.8 mΩ @ 10 V	110 A	
40 V	4.4 mΩ @ 4.5 V	HUA	



**N-CHANNEL MOSFET** 



LFPAK4 CASE 760AB



**MARKING** 

2D9N04CL = Specific Device Code A = Assembly Location

WL = Wafer Lot Y = Year W = Work Week

### **ORDERING INFORMATION**

See detailed ordering, marking and shipping information in the package dimensions section on page 5 of this data sheet.

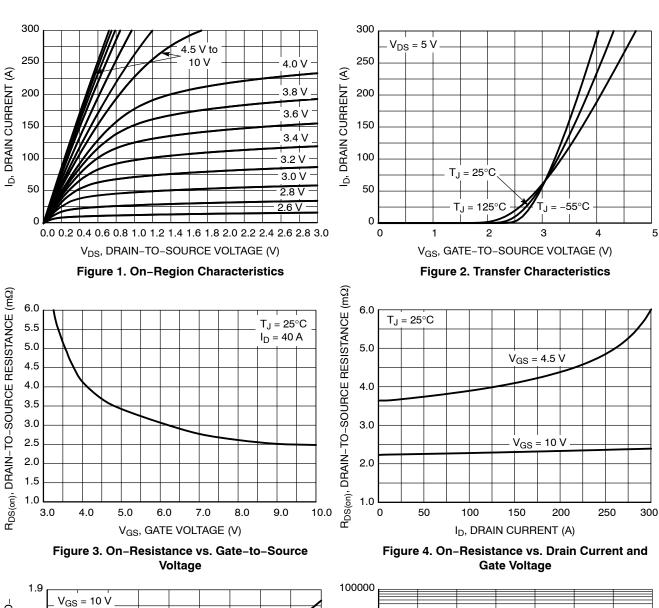
# **ELECTRICAL CHARACTERISTICS** ( $T_J = 25^{\circ}C$ unless otherwise specified)

Parameter	Symbol	Test Condition		Min	Тур	Max	Unit	
OFF CHARACTERISTICS								
Drain-to-Source Breakdown Voltage	V <sub>(BR)DSS</sub>	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		40			V	
Drain-to-Source Breakdown Voltage Temperature Coefficient	V <sub>(BR)DSS</sub> /				1.6		mV/°C	
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	$V_{GS} = 0 V$	T <sub>J</sub> = 25 °C			10		
		$V_{DS} = 40 \text{ V}$	T <sub>J</sub> = 125°C			250	μΑ	
Gate-to-Source Leakage Current	I <sub>GSS</sub>	$V_{DS} = 0 \text{ V}, V_{GS}$	; = 20 V			100	nA	
ON CHARACTERISTICS (Note 4)								
Gate Threshold Voltage	V <sub>GS(TH)</sub>	$V_{GS} = V_{DS}, I_D$	= 60 μΑ	1.2		2.0	V	
Threshold Temperature Coefficient	V <sub>GS(TH)</sub> /T <sub>J</sub>				-5.3		mV/°C	
Drain-to-Source On Resistance	R <sub>DS(on)</sub>	V <sub>GS</sub> = 4.5 V	I <sub>D</sub> = 40 A		3.5	4.4	0	
		V <sub>GS</sub> = 10 V	I <sub>D</sub> = 40 A		2.3	2.8	mΩ	
Forward Transconductance	9 <sub>FS</sub>	V <sub>DS</sub> =15 V, I <sub>D</sub>	= 40 A		120		S	
CHARGES, CAPACITANCES & GATE RES	SISTANCE							
Input Capacitance	C <sub>ISS</sub>				2100			
Output Capacitance	C <sub>OSS</sub>	$V_{GS}$ = 0 V, f = 1 MHz, $V_{DS}$ = 20 V			1000		pF	
Reverse Transfer Capacitance	C <sub>RSS</sub>				42			
Total Gate Charge	Q <sub>G(TOT)</sub>	V <sub>GS</sub> = 4.5 V, V <sub>DS</sub> = 20 V; I <sub>D</sub> = 40 A			16		nC	
Total Gate Charge	Q <sub>G(TOT)</sub>				35			
Threshold Gate Charge	Q <sub>G(TH)</sub>	$V_{GS} = 10 \text{ V}, V_{DS} = 20 \text{ V}; I_D = 40 \text{ A}$			4.0		nC	
Gate-to-Source Charge	Q <sub>GS</sub>				7.0			
Gate-to-Drain Charge	$Q_{GD}$				5.0			
Plateau Voltage	$V_{GP}$				3.2		V	
SWITCHING CHARACTERISTICS (Note 5)								
Turn-On Delay Time	t <sub>d(ON)</sub>				11			
Rise Time	t <sub>r</sub>	$V_{GS} = 4.5 \text{ V}, V_{DS}$	<sub>S</sub> = 20 V,		110		] <sub>no</sub>	
Turn-Off Delay Time	t <sub>d(OFF)</sub>	$V_{GS}$ = 4.5 V, $V_{DS}$ = 20 V, $I_{D}$ = 40 A, $R_{G}$ = 1 $\Omega$			21		ns -	
Fall Time	t <sub>f</sub>				5.0			
DRAIN-SOURCE DIODE CHARACTERIST	rics							
Forward Diode Voltage	$V_{SD}$	V <sub>GS</sub> = 0 V,	$T_J = 25^{\circ}C$		0.84	1.2		
			T <sub>J</sub> = 125°C		0.72		V	
Reverse Recovery Time	t <sub>RR</sub>	$V_{GS} = 0 \text{ V, } dls/dt = 100 \text{ A/}\mu s,$ $l_{S} = 40 \text{ A}$			41			
Charge Time	t <sub>a</sub>				19		ns	
Discharge Time	t <sub>b</sub>				22		1	
Reverse Recovery Charge	Q <sub>RR</sub>				31		nC	

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

Pulse Test: pulse width ≤ 300 μs, duty cycle ≤ 2%.
 Switching characteristics are independent of operating junction temperatures.

# **TYPICAL CHARACTERISTICS**



 $T_{.1} = 150^{\circ}C$ 10000 IDSS, LEAKAGE (nA)  $T_J = 125^{\circ}C$ 1000  $T_J = 85^{\circ}C$ 100 10 75 100 125 5 15 25 35 150 175 T<sub>J</sub>, JUNCTION TEMPERATURE (°C) V<sub>DS</sub>, DRAIN-TO-SOURCE VOLTAGE (V)

Figure 5. On-Resistance Variation with **Temperature** 

50

25

R<sub>DS(on)</sub>, NORMALIZED DRAIN-TO-SOURCE RESISTANCE 0 T E T L 6 T E 2 Y

0.7

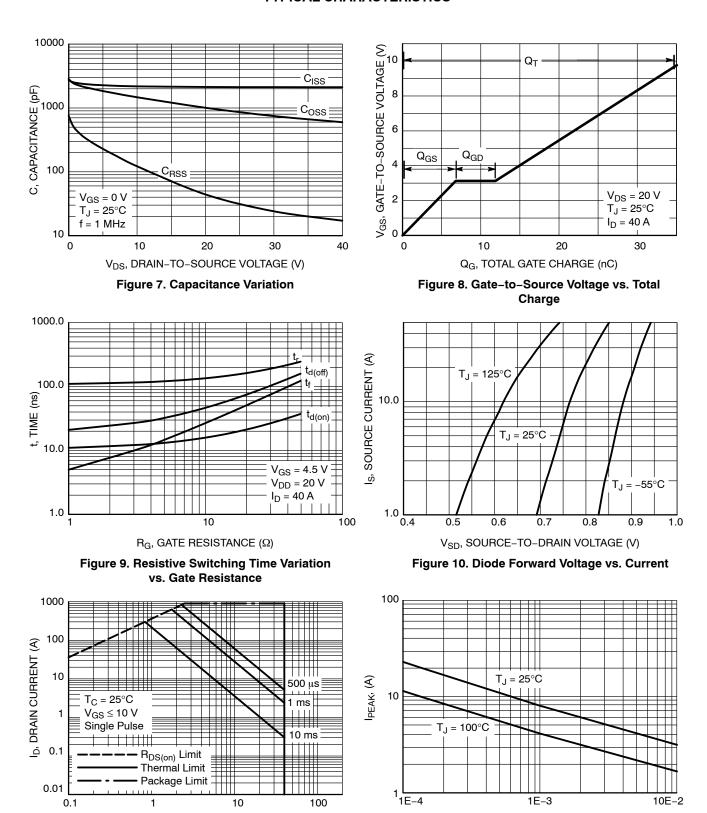
-50

I<sub>D</sub> = 40 A

-25 0

Figure 6. Drain-to-Source Leakage Current vs. Voltage

# **TYPICAL CHARACTERISTICS**



 $V_{DS}\left(V\right)$  Figure 11. Safe Operating Area

# **TYPICAL CHARACTERISTICS**

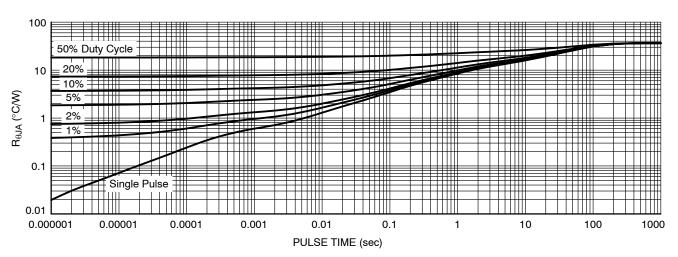


Figure 13. Thermal Characteristics

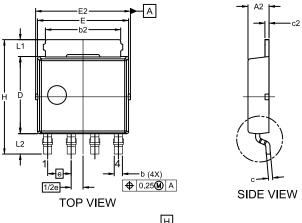
# **DEVICE ORDERING INFORMATION**

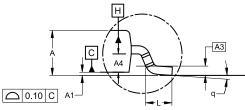
Device	Marking	Package	Shipping <sup>†</sup>
NTMYS2D9N04CLTWG	2D9N04CL	LFPAK4 (Pb-Free)	3000 / Tape & Reel

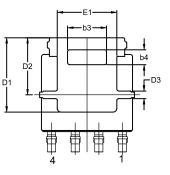
<sup>†</sup>For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

# PACKAGE DIMENSIONS

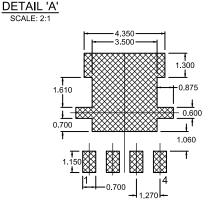
# LFPAK4 5x6 CASE 760AB **ISSUE A**











RECOMMENDED MOUNTING **FOOTPRINT** 

### NOTES:

- DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
- CONTROLLING DIMENSION: MILLIMETERS.
- DIMENSIONS D AND E DO NOT INCLUDE MOLD FLASH, PROTRUSIONS, OR BURRS. MOLD FLASH PROTRUSIONS OR GATE BURRS SHALL NOT EXCEED 0.150mm PER SIDE.
- DIMENSIONS D AND E ARE DETERMINED AT THE OUTERMOST EXTREMES OF THE PLASTIC BODY.
- DATUMS A AND B ARE DETERMINED AT DATUM PLANE H.

UNIT IN MILLIMETER					
DIM	MIN	NOM	MAX		
Α	1.10	1.20	1.30		
A1	0.00	0.08	0.15		
A2	1.10	1.15	1.20		
А3		0.25			
A4	0.45	0.50	0.55		
b	0.40	0.45	0.50		
b2	3.80	4.10	4.40		
b3	2.00	2.10	2.20		
b4	0.70	0.80	0.90		
С	0.19	0.22	0.25		
c2	0.19	0.22	0.25		
D	4.05	4.15	4.25		
D1	-	-	4.20		
D2	3.0	3.10	3.20		
D3	0.30	0.40	0.50		
Е	4.80	4.90	5.00		
E1	3.10	3.20	3.30		
E2	5.00	5.15	5.30		
е	1.27 BSC				
I	6.00	6.15	6.30		
Г	0.40	0.65	0.85		
L1	0.80	0.90	1.00		
L2	0.80	1.05	1.30		
q	0°	4°	8°		

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